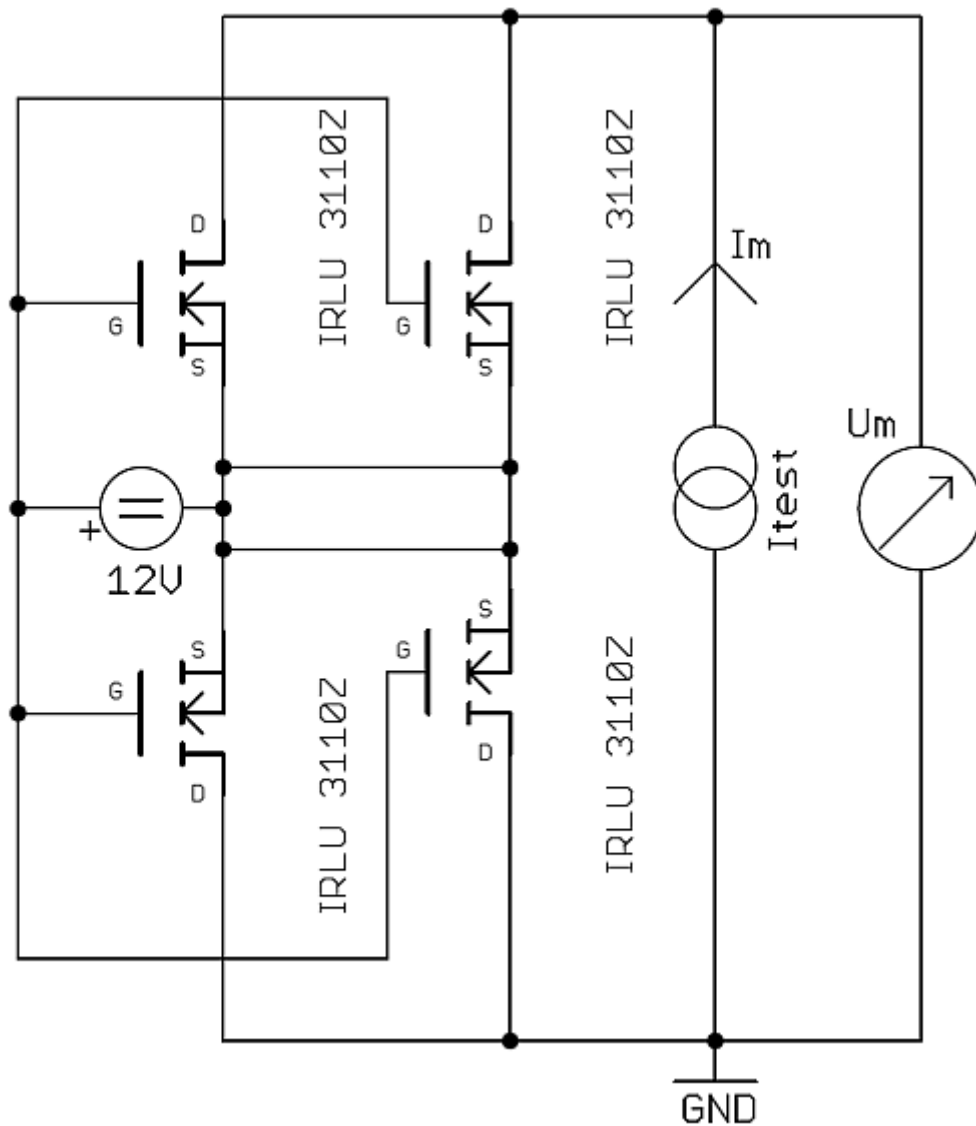


Appendix A

SSR and THD

The first thought when hearing SSR is, that it creates THD. But why ? There are no measurements around, but the feeling it creates THD is widely spreaded, especially in audiophile circles.

So making a simulation as first step is a good idea. Fortunately, for the choosen FETs simulation models are available from International Rectifier, wich normally give good results regarding the real devices. So, have a look on fig.1 to see the simulation schematic:

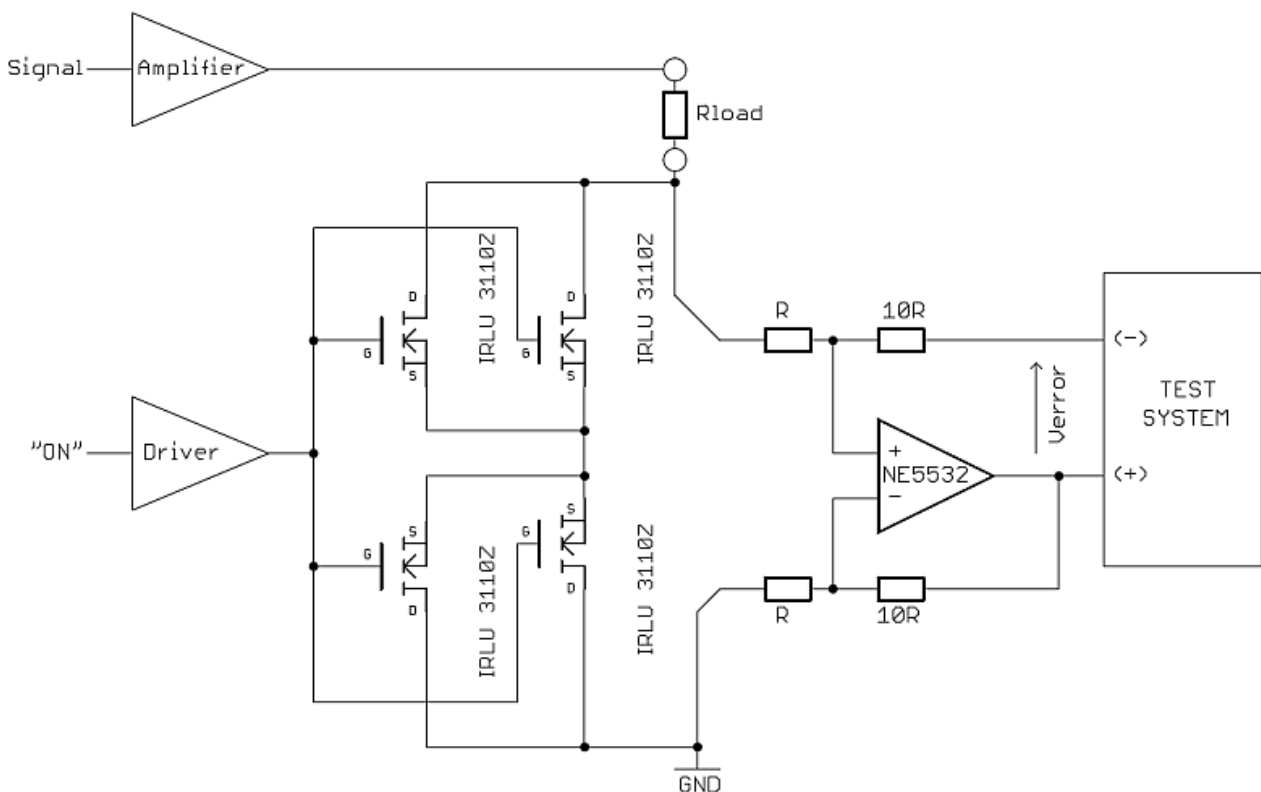


Now, you can run a DC Transfer Analysis with Itest as parameter (0.01A .. 10A).

Then, knowing that $R=U/I$, you can plot $R=U_m/I_m$ and see a very slow ascending line. This is the R_{dson} over current. After zooming in you see that R_{dson} will raise with $\sim 1.35\mu\text{Ohm} / 10\text{A}$. Having 11mOhm as constant R_{dson} and 135nOhm per A, the ratio will be ~ 80.000 . If using 4 Ohms as usual load, the factor 4 Ohms/10mOhms will be 400. The total ratio of RI to nonlinearity will be $80.000 \times 400 = 32$ million (per Ampere) and this is somewhere in the 150 dB range. Now using not 1A but 10A as peak current, THD will be in the >130 dB range. From simulation, the amplifier would be always worse than the SSR.

Measuring total SSR drop voltage U_m and current I_m when running 10Apk and then building R_{dson} gives a ΔR_{dson} of $0.64\mu\text{ohms}$ resulting in 125dB.

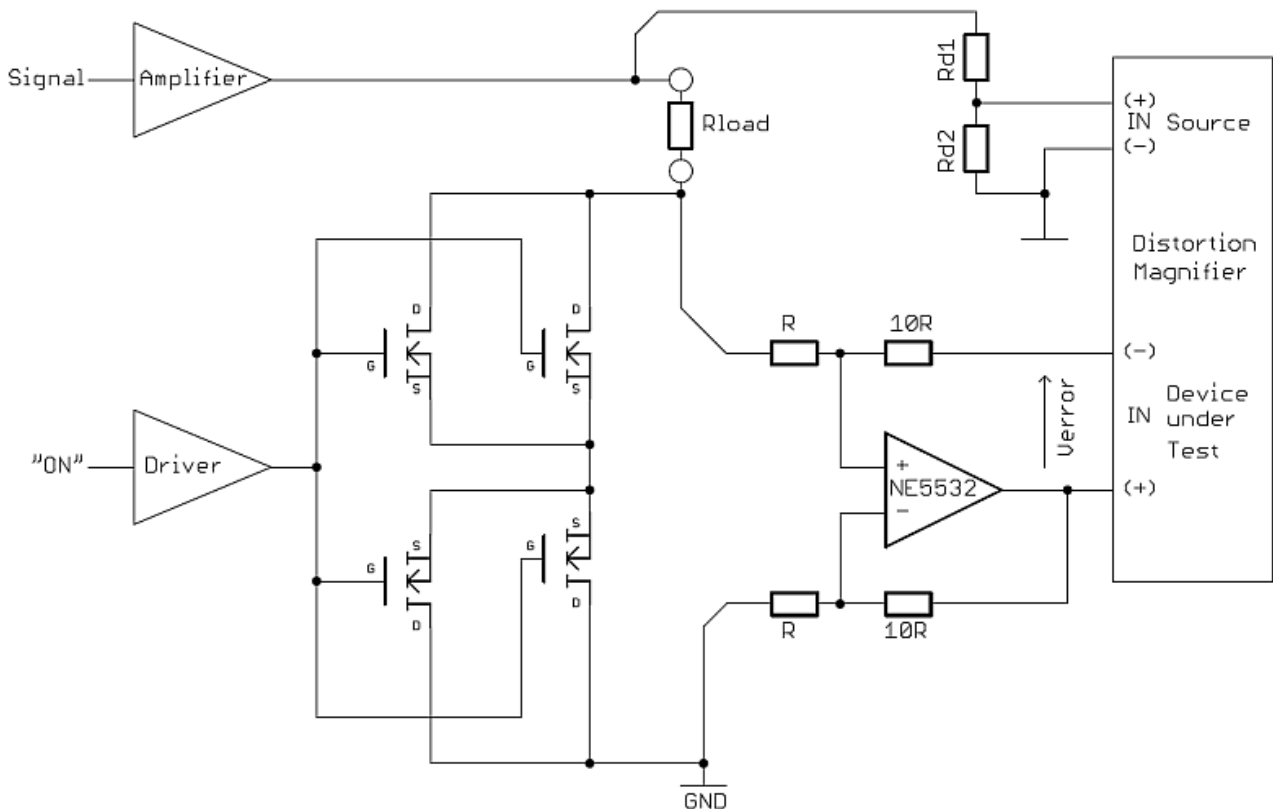
Going to the real world, the THD can be measured best with a real amplifier, because of the high currents necessary. See fig.2 for measurement arrangement:



The test setup consist of an amplifier capable of several amperes output current, a load resistance in the range usually used , like 4 or 8 ohms, the SSR driver, a differential preamplifier with gain=10 and a test system to measure the THD figure. The test system can be something like a professional one, a distortion magnifier or a good soundcard. Now, a sine signal should be inserted with a level so that, at the load, a usefull current flow is established (e.g. 5A..7A peak). Then the voltage drop over the SSR is measured and amplified by 10. With the FET's given and 7.5A peak, my test setup gives a voltage drop of $\sim 100\text{mV}$ peak wich results in $\sim 1\text{V}$ peak level at the analyzer input. Measuring the THD now, you see the two things, the THD the amplifier makes and the THD resulting from the SSR. With normal test equipment, you can only measure both and if you compare it with the amplifier THD, you can see if it get's worse or not.

Going deeper

Going deeper is possible, but you need a distortion magnifier with the source input connected to the downscaled amplifier output and the DUT input connected to the differential amplifiers output. Then, the magnifier subtracts its source input from the signal related part of the voltage over the SSR and remaining is the SSRs THD only. The THD could now be magnified by 10 or 100.



The THD of the SSR can now be calculated as

$$\text{THD} = (G_{da} / G_{dm}) * (R_{dson} / R_{load}) * (\text{Distortion magnifier output})$$

with

G_{dm} Gain of distortion magnifier (x1, x10, x100 typical)

G_{da} Gain of differential Amplifier (x10 in with values given)

R_{load} Load resistance in ohms

R_{dson} Static R_{dson} of SSR = $\sim (V_{error} / G_{da}) / (V_{outpk} / R_{load})$ if $R_{dson} \ll R_{load}$

$10R; R$ $10R = 10x$ value of R , $R=100$; $10R=1k$ is useful

typical values: $G_{dm} = 100$; $G_{da} = 10$; $R_{load} = 4\text{ohms}$; $R_{dson} = 10\text{mohms}$

$$\text{THD} = (10/100) * (10\text{m}/4) * \text{Output} = 250\text{E-}6 * \text{Output}$$

The THD of the NE5532 can be ignored, because you will get a voltage in the 100mV range multiplied by ten giving ~ 1 V. If the NE5532 would have a THD of -90dB only, than the SSRs THD is by the factor R_{load} / R_{dson} better than measured (regarding the formula given above). With this factor of 400 (e.g.), you would get another 50dB and end up in the 140dB range. That's low enough, even for the best amplifiers.

Note: You must calculate the Rd1/Rd2 divider so that at the measurement voltage $\sim 1\text{Vpk}$ is measured at the Source input. With a slightly modified Distortion magnifier (gain is $-3\text{dB}..+3\text{dB}$) the test should work.

Other effects

We have seen that the THD of a SSR is only dependent on its R_{dson} variation. The first parameter, Current, we have examined earlier. But there are others and one additional nonlinearity, if not the 2nd major one, is temperature. The nonlinearity wouldn't matter, if temperature rise is slowly, e.g. $1^\circ\text{C}/\text{sec}$. But if it rises very fast, you would modulate the R_{dson} by temperature which is signal dependent !

The R_{dson} vs. Temp. graph in the IRLR3110 datasheet shows us, that for a $0..100^\circ\text{C}$ change the R_{dson} varies from $0.75 \cdot R_{\text{dson}}$ to $1.75 \cdot R_{\text{dson}}$ (relative to 25°C). Approximating it with a line and $14\text{m}\Omega$, we get $10.5\text{m}\Omega$ to $24.5\text{m}\Omega$ for 100°C change, giving $140\mu\Omega$ per $^\circ\text{C}$. Now, how warm would the die be ? Using 2 paralleled devices, like done here, everyone gets half the current. This is $5\text{A}/\text{device}$ if max is 10A . Power dissipation is now $I \cdot I \cdot R = 5\text{A} \cdot 5\text{A} \cdot 14\text{m}\Omega = 350\text{mW}_{\text{peak}}$ and $3.5\text{A} \cdot 3.5\text{A} \cdot 14\text{m}\Omega = 175\text{mW}_{\text{rms}}$ per device. Worst thing what can happen are low frequency pulses, because of at high frequencies (e.g. $> 1\text{kHz}$), the die wouldn't heat up and cool down fast enough.

The internal thermal resistance is $1.05\text{K}/\text{W}$, so giving $\sim +0.37^\circ\text{C}$ at 350mW and 0.184K at 175mW . These values related with the $140\mu\Omega/\text{K}$ give a thermal nonlinearity of $52\mu\Omega/\text{spk}$ or $26\mu\Omega/\text{rms}$. Our 40Ω load divided by $52\mu\Omega$ will give $\sim 98\text{dB}$ THD, the $26\mu\Omega/\text{rms}$ will give $\sim 103\text{dB}$. This effect covers the effect of current dependent R_{dson} completely ! But fortunately, Audio wouldn't consist of power peaks only. Lowering the volume by 6dB will give 15Vpk only, which pushes 3.75Apk through the load, so a single device sees 1.88A which results in $1.88\text{A} \cdot 1.88\text{A} \cdot 14\text{m}\Omega = 50\text{mW}_{\text{peak}}$, which are multiplied by 1.05 , giving 52mK of temperature rise and therefore $7.3\mu\Omega$. In the end, the ratio is $\sim 115\text{dB}$ and getting even lower with decreasing output voltage.

Also here, a simulation was done with the following results:

$10.49\text{m}\Omega$ @ 0°C and $11.05\text{m}\Omega$ @ 100°C with 1A current giving $115\mu\Omega$ per 100°C and $1.15\mu\Omega$ per 1°C . Let it run with 10A_{peak} give an P_{peak} of 270mW per device which would result in 0.28°C temperature swing per device. Total R_{dson} change is therefore $1.15\mu\Omega \cdot 0.28^\circ\text{C} = 322\text{n}\Omega$. The ratio R_{load} and ΔR_{dson} is then 142dB . So simulation gives better results than datasheet and assumptions do.

Also take into account, that we assumed that there is almost no thermal mass of the device, averaging the temperature rise and cool down, so the values given here are the worst case, and values are better in reality. Using a more realistic 20°C to 80°C range (60°C), then you get $14\text{m}\Omega..21\text{m}\Omega$, resulting in $120\mu\Omega$. This is a factor, giving another 1.4dB and for very small temperature changes around the $20^\circ\text{C}-40^\circ\text{C}$, the value is even lower.

But for higher currents than these 5A per device, other FETs or more paralleled ones should be chosen.

The third, but mainly negligible, effect is V_{gs} , the gate to source voltage. R_{dson} is dependent of V_{gs} . But usually, it shouldn't be a problem to hold V_{gs} constant and V_{gs} should be in a range, where its value has almost no influence on R_{dson} . If you go up to 12V and higher, the dependencies are very low.

Small Signal SSR:

For interest I have added some information of small signal FETs. But take care of the output capacity if the FET is set to OFF.

All values simulated with SSR in GND line, so switching R=1k to GND ("Lowside").
VgsON=12V;VgsOFF=0V

Simulation results:

FET	Rdson static [Ohms]	delta Rdson 1nA .. 2mA [Ohms]	Voltage at SSR [V/mA]	OFF leakage at 1V/1kohm	Ratio delta Rdson to 1kohm	THD 2V/1kohm [dB]
BSS138	2,25	5,1 μ ohms	2,25m	762pA	1,96E+008	> 160
BSS138, PI*	4,5	15 μ ohms/0.5mA	4,5m		6,60E+007	155
BS170	4,4	40 nohms	4,4m	5,6pA	2,50E+010	> 160
BSS123	5,2	10 μ ohms	5,2m	33pA	> 1,0E+008	> 160
IRLML0030	0,04	240 nohms	35 μ	8,12nA	1,00E+014	> 180

*IRLML0030:

Datasheet -> $\Delta R_{dson} = 3m\Omega / 25A = 240nohm$

Cout ~ 100pF --> 1kOhms:-3dB @ 800kHz (OFF)

cost ~ 0,20€/piece, Jan 2015

FETs simulated from Signal Source to R=1k ("Highside"):

FET	Rdson static [Ohms]	delta Rdson 1nA .. 2mA [Ohms]	Voltage at SSR [V/mA]	OFF leakage at 1V/1kohm	Ratio delta Rdson to 1kohm	THD 2V/1kohm [dB]
BSS138, PI*	4,5	15 μ ohms/0.5mA	4,5m	1E-17 A	6,60E+007	155

FET	Loss @ 22kHz* (OFF)	Loss @ 100kHz* (OFF)	Loss @ 1 Mhz* (OFF)
IRLML0030	-36 dB	-22 dB	-4,5 dB
BSS138	-58 dB	-45 dB	-25 dB

*Loss means by what factor the original source signal is suppressed by the turned OFF FET

*PI configuration: